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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
	AA	4,792,958	12/20/88	OHBA, et al.				
	AB	4,809,287	02/28/89	OHBA, et al.				
	AC	4,835,117	05/30/89	OHBA, et al.				
	AD ·	4,949,349	08/14/90	OHBA, et al.				
	AE	4,910,743	03/20/90	OHBA, et al.				
	AF	4,928,285	05/22/90	KUSHIBE, et al.				
	AG	4,893,313	01/09/90	HATAKOSHI, et al.				
	AH	5,076,800	12/31/91	MILNES, et al.			· · · · · · · · · · · · · · · · · · ·	
	Al	5,036,521	07/30/91	HATAKOSHI, et al.				
	AJ	5,168,077	12/01/92	ASHIZAWA, et al.				
******	AK	5,042,043	08/20/91	HATANO, et al.				
-	AL	5,005,057	04/02/91	IZUMIYA, et al.		1		
	AM	5,079,184	01/07/92	HATANO, et al.		††		
	AN	5,103,271	04/07/92	IZUMIYA, et al.				
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Form PTO 1449 (Modified)	9 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			248760US0RDCONT		New Continuation of 10/188,744		
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
	AA	5,228,044	07/13/93	ОНВА				
	AB	5,235,194	08/10/93	IZUMIYA, et al.				
	AC	5,273,933	12/28/93	HATANO, et al.				
	AD	5,317,167	05/31/94	IZUMIYA, et al.				
	AE		07/11/95	HATANO, et al.			•	
·	AF		04/01/97	HATANO, et al.				
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	AH		12/07/99	HATANO, et al.			·	
	Al		06/05/01	Y. OHBA, et al.				
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
	AA	5,146,465	09/92	KHAN, et al.				
	AB	6,259,122	07/01	OTA, et al.				
	AC	5,875,052	02/99	SHMAGIN, et al.		<u> </u>		
	AD	6,306,672 B1	10/01	KIM	<u> </u>	<u> </u>		
	AE	6,046,464	04/00	SCHETZINA			·	
	AF	6,440,823 B1	08/02	VAUDO, et al.	<u> </u>	<u> </u>	·	
	AG	5,929,467	07/99	KAWAI, et al.				
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